RF Hot Switch Reliability of MEMS Switches

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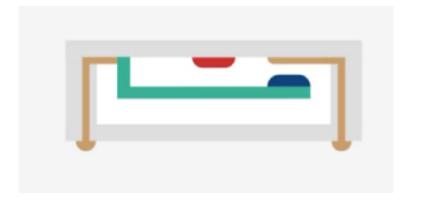
June 2023

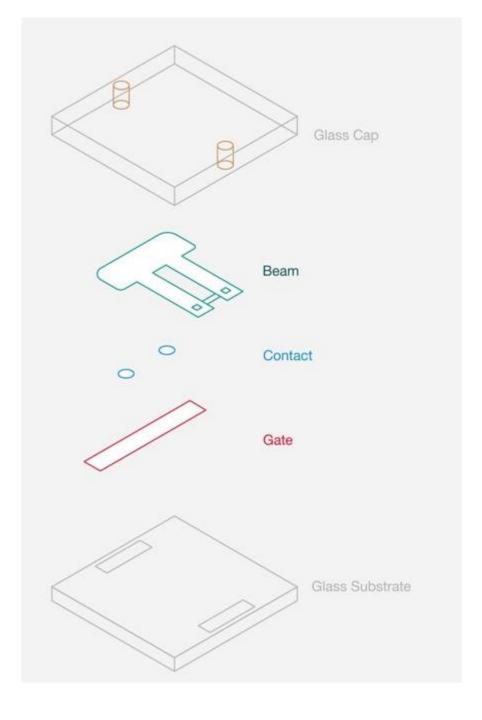




MEMS Contact Switches

- High Voltage Gate signal closes the switch
- When the gate voltage is turned on, the beam is pulled in and connects to the contact

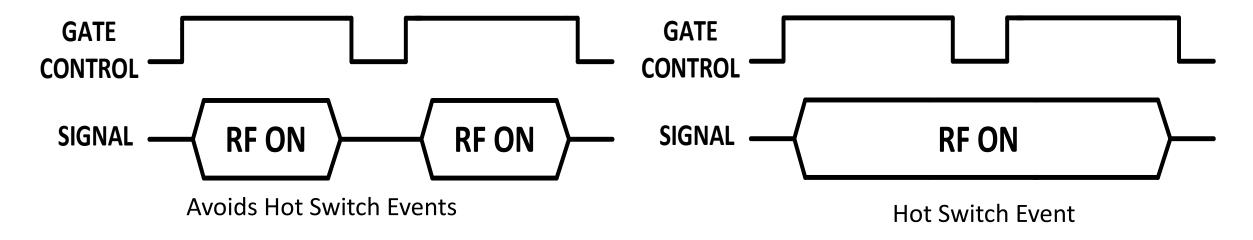




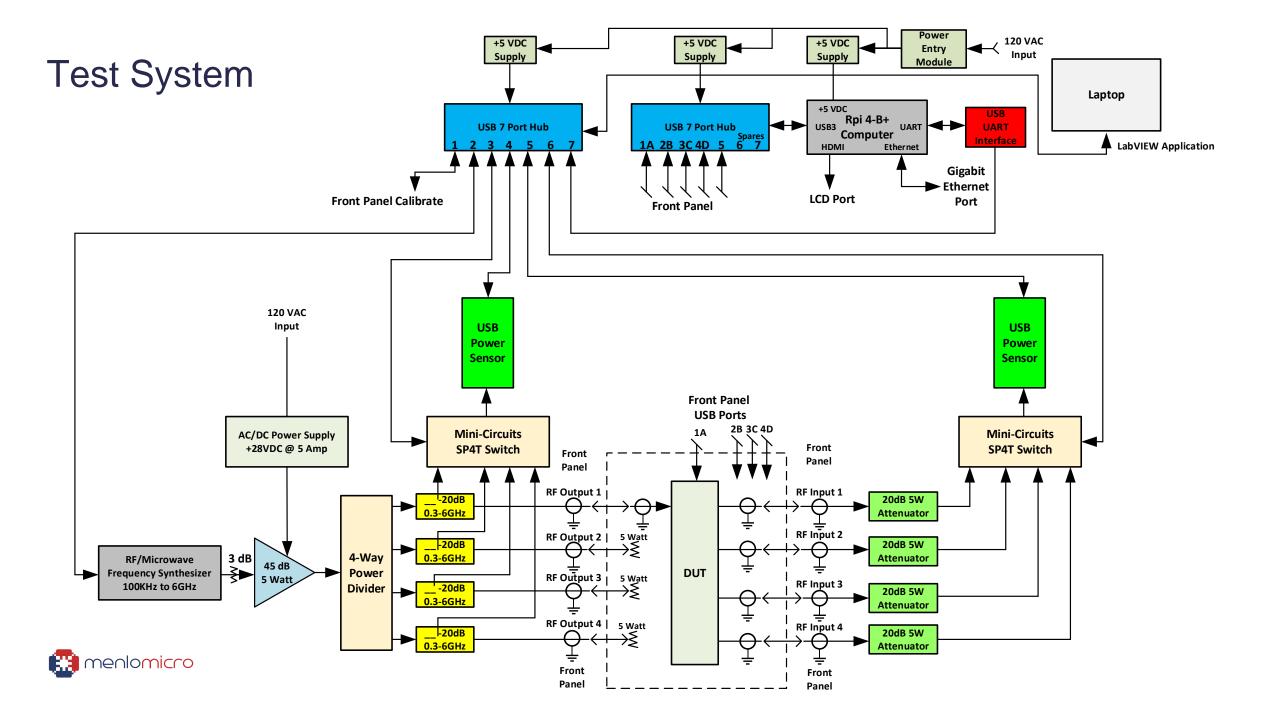


Hot Switching Introduction

- Hot Switch events occur when a switch changes state with a load signal turned on
 - For best performance, avoid hot switch events
- Hot Switch events can exacerbate failure mechanisms such as wear-out and micro-welding
- Surface materials can affect the longevity of switches
 - Using hard material as contact surface can provide resistance to wear and demonstrates capability
 of withstanding high-intensity arcing and to be free from sticking or pitting
 - Hard material coated in Gold (Au) on the MEMS switch contacts can extend the life

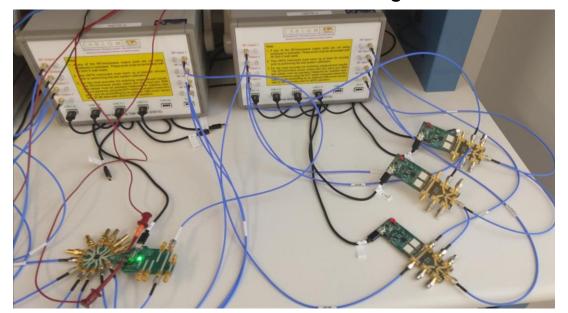






Test Methodology

- Channel under test was cycled at 10kHz
 - On State (Insertion Loss) and Off State (Isolation) measurements taken at set intervals (ex. Every 100,000 cycles)
 - All unused channels terminated with 50Ω loads
 - A thru line was also measured to ensure no anomalies in system
- 2 Failure modes:
 - "Stuck open" defined as on-state measurement indicating switch is in the off-state
 - "Stuck closed" defined as off-state measurement indicating switch is in the on-state





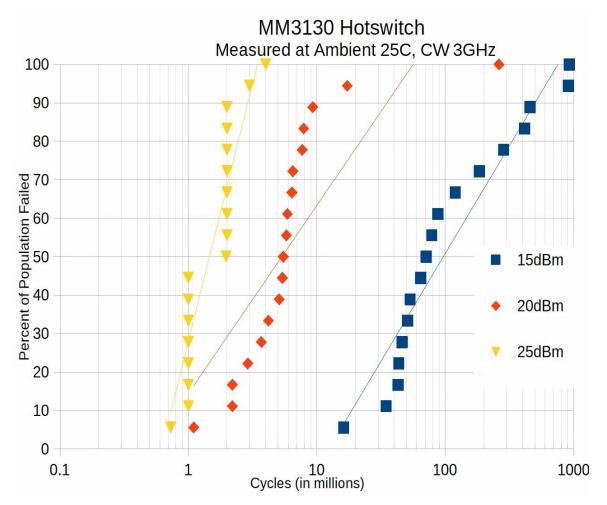
Test Conditions

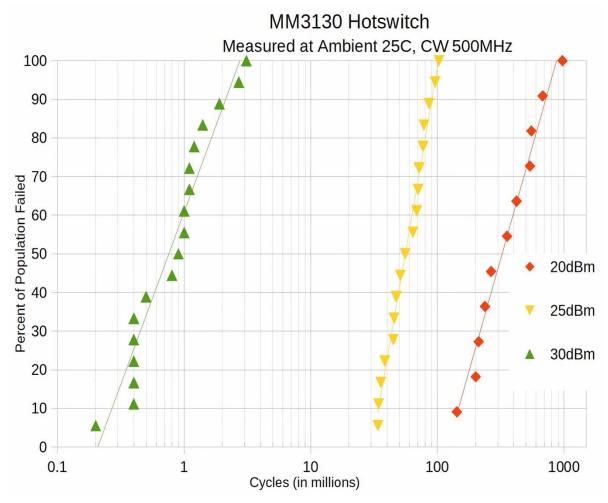
- Two switch topologies tested: SP4T and SPST
- All testing was completed at room temperature

| Device | | Conditions | |
|--------|-------------------|------------|--------------|
| Name | Topology | Frequency | Power Levels |
| MM3130 | 6 x SPST | 500 MHz | 20 dBm |
| | w/External Driver | | 25dBm |
| | | | 30 dBm |
| | | 3 GHz | 15 dBm |
| | | | 20 dBm |
| | | | 25 dBm |
| MM3100 | 6 x SPST | 500 MHz | 20 dBm |
| | w/Internal Driver | | 25dBm |
| | | | 30 dBm |
| MM5130 | SP4T | 500 MHz | 20 dBm |
| | | | 25dBm |
| | | | 30 dBm |



MM3130 Results





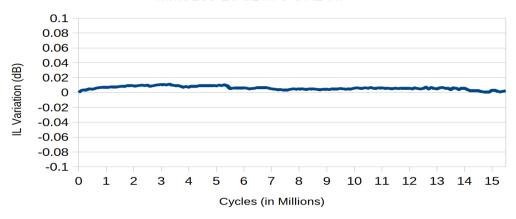
Generally, the switches failed "stuck closed"



MM3130 Results (cont.)

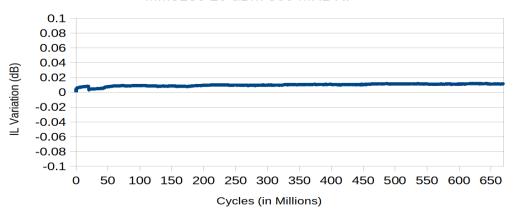
IL Variation Over Cycles

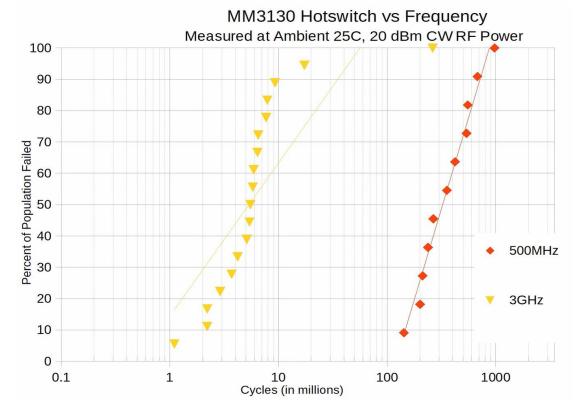
MM3130 20 dBm 3 GHz RF



IL Variation Over Cycles

MM3130 20 dBm 500 MHz RF

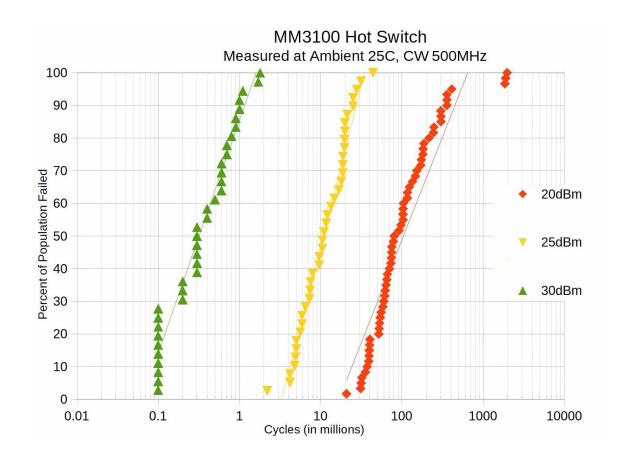




- Insertion Loss variation was less than 0.02dB over the lifetime of the switch
- Higher frequencies has a greater impact on switch lifetime



MM3100 Results



IL Variation Over Cycles MM3100 20 dBm 500 MHz RF



150

Cycles (in Millions)

200

250

300

350

100

- Generally, the switches failed "stuck closed"
- Insertion Loss variation was less than 0.02dB over the lifetime of the switch

IL Variation (dB)

-0.02 -0.04

-0.06 -0.08

-0.1

50



MM3100 RF vs DC Hot Switching

MM3100 Hot Switch RF vs DC 50Ω 500MHz CW RF System, 47Ω DC System, Ambient 25C 100 90 80 70 70 Pelipi God 40 30 MM3100 Hot Switch RF vs DC 50Ω 500MHz CW RF System, 47Ω DC System, Ambient 25C V DC HOT SWITCH V=2.236 RF Hot Switch 20dBm/ 2.236VRMS

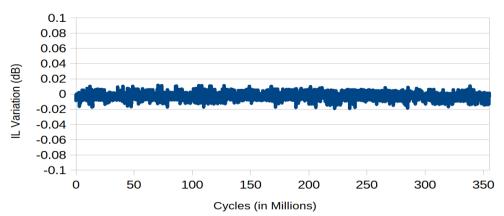
Cycles (in millions)

1000

100

IL Variation Over Cycles





Contact Resistance over Hot Switch Cycles

Measured at Ambient 25C 1.12 1.08 1.04 0.92 0.88 0.84 8.0 200 400 600 800 1000 1200 1400 Cycles (in Millions)

PRF system run at 20dBm, 50 Ω , V_{RMS} =2.24V, DC system run at 2.24V with 47 Ω load

10000

- Insertion Loss variation was less than 0.02dB over the lifetime of the switch
- Contact resistance varied by less than 0.05Ω over the lifetime of the switch

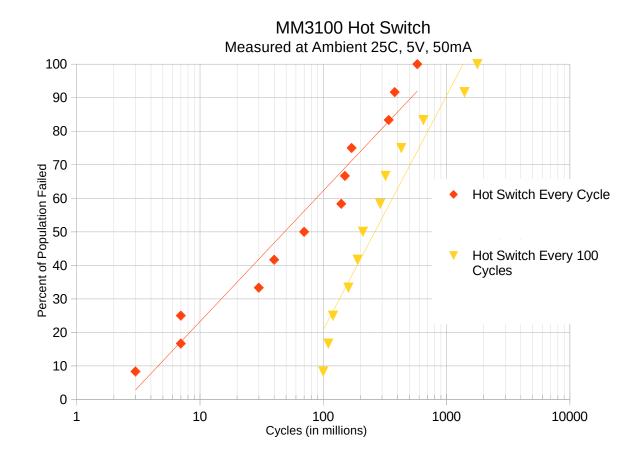


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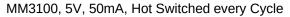
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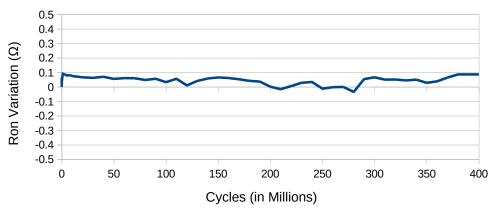
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Intermittent Hot Switch Events



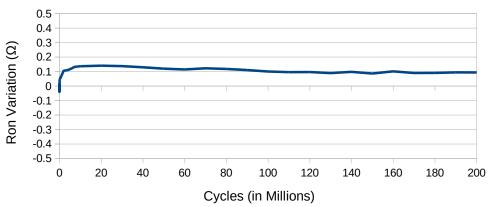
On-State Resistance Variation Over Cycles





On-State Resistance Variation Over Cycles

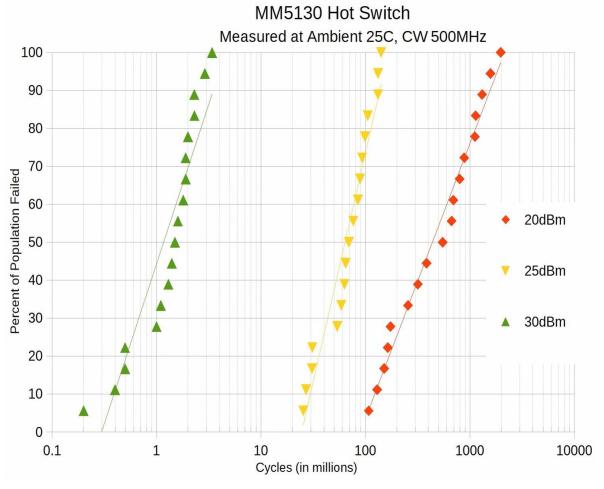
MM3100, 5V, 50mA, Hot Switched every 100 Cycle



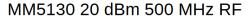
Intermittent hot switch events will have less of an impact on lifetime

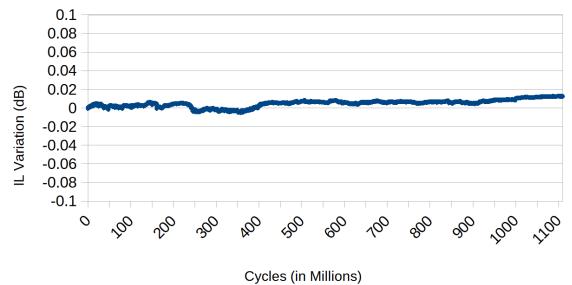


MM5130 Results



IL Variation Over Cycles





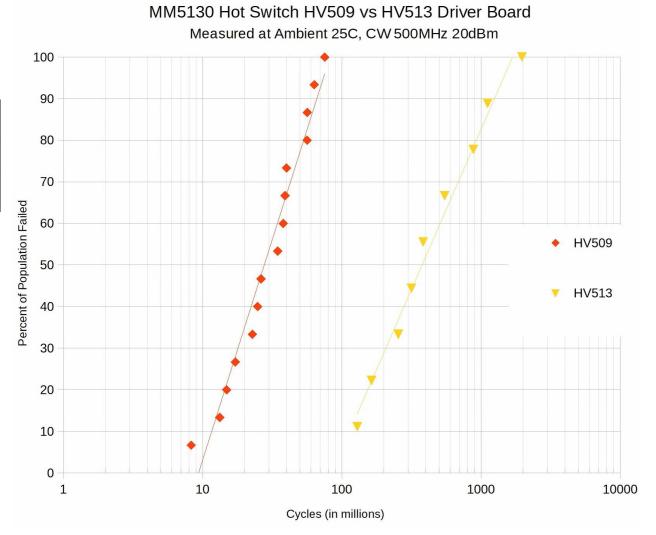
- Generally, the switches failed "stuck closed"
- Insertion Loss variation was less than 0.02dB over the lifetime of the switch



Effects of Gate Voltage Slew Rate on Life Span

| Driver | Rise Time | Fall Time |
|--------|-----------|-----------|
| HV513 | 2920 ns | 653 ns |
| HV509 | 2171 ns | 5046 ns |

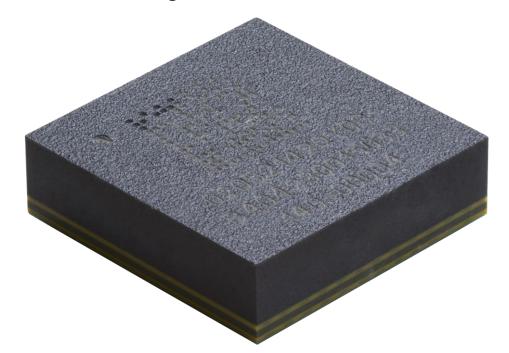
- The slew rate of the driver affects the hot switch lifetime of the switch
 - A quicker slew rate will result in better hot switch lifetime





Conclusions

- Although lifetime was degraded, over 100,000 cycles was observed with 30dBm (1W) hot switch events.
- Surface materials can affect the longevity of switches
 - Using hard material as contact surface can provide resistance to wear and demonstrates capability of withstanding high-intensity arcing and to be free from sticking or pitting
 - Hard material coated in Gold (Au) on the MEMS switch contacts can extend the life
- Slew rate impacts hot switch lifetime, quicker slew rate is better for longevity
- Protection circuits can be used to mitigate hot switch events and improve switch lifetime.







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